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APPLICATION NO).	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/520,099		01/04/2005	Ryoji Hoshi	122336	9147
25944	7590	07/26/2006		EXAMINER	
		OGE, PLC	HITESHEW, FELISA CARLA		
P.O. BOX 19928 ALEXANDRIA, VA 22320		A 22320		ART UNIT	PAPER NUMBER
				1722	
				DATE MAILED: 07/26/2006	

Please find below and/or attached an Office communication concerning this application or proceeding.

	Application No.	Applicant(s)				
Office Action Summary	10/520,099	HOSHI ET AL.				
Office Action Summary	Examiner	Art Unit				
The MAII INC DATE of this communication and	Felisa C. Hiteshew	1722				
The MAILING DATE of this communication appe Period for Reply	ears on the cover sheet with the c	orrespondence address				
A SHORTENED STATUTORY PERIOD FOR REPLY WHICHEVER IS LONGER, FROM THE MAILING DA - Extensions of time may be available under the provisions of 37 CFR 1.131 after SIX (6) MONTHS from the mailing date of this communication. - If NO period for reply is specified above, the maximum statutory period with a failure to reply within the set or extended period for reply will, by statute, any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).	TE OF THIS COMMUNICATION 6(a). In no event, however, may a reply be tim Il apply and will expire SIX (6) MONTHS from cause the application to become ABANDONE!	N. nely filed the mailing date of this communication. D (35 U.S.C. § 133).				
Status						
1) Responsive to communication(s) filed on						
<u> </u>	==, /=					
3) Since this application is in condition for allowance except for formal matters, prosecution as to the merits is						
closed in accordance with the practice under Ex parte Quayle, 1935 C.D. 11, 453 O.G. 213.						
Disposition of Claims						
4) ☐ Claim(s) 12-40 is/are pending in the application 4a) Of the above claim(s) is/are withdraw 5) ☐ Claim(s) 24-39 is/are allowed. 6) ☐ Claim(s) 12-23 and 40 is/are rejected. 7) ☐ Claim(s) is/are objected to. 8) ☐ Claim(s) are subject to restriction and/or	n from consideration.					
Application Papers						
9) The specification is objected to by the Examiner. 10) The drawing(s) filed on is/are: a) acception acceptance acception acceptance acception acceptance	pted or b) objected to by the E rawing(s) be held in abeyance. See on is required if the drawing(s) is obj	e 37 CFR 1.85(a). ected to. See 37 CFR 1.121(d).				
Priority under 35 U.S.C. § 119	·					
a) Acknowledgment is made of a claim for foreign p a) All b) Some * c) None of: 1. Certified copies of the priority documents 2. Certified copies of the priority documents 3. Copies of the certified copies of the priority application from the International Bureau * See the attached detailed Office action for a list o	have been received. have been received in Application by documents have been receive (PCT Rule 17.2(a)).	on No d in this National Stage				
Attachment(s) 1) Notice of References Cited (PTO-892) 2) Notice of Draftsperson's Patent Drawing Review (PTO-948) 3) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08) Paper No(s)/Mail Date see attached paper. S. Patent and Trademark Office	4) Interview Summary (Paper No(s)/Mail Da 5) Notice of Informal Pa 6) Other:					

Priority

1. Receipt is acknowledged of papers submitted under 35 U.S.C. 119(a)-(d), which papers have been placed of record in the file.

Information Disclosure Statement

The PTOL 1449 has been received, reviewed and considered.

Claim Rejections - 35 USC § 112

2. Claims 12, 24 and 40 are rejected under 35 U.S.C. 112, second paragraph, as being indefinite for failing to particularly point out and distinctly claim the subject matter which applicant regards as the invention.

In claim 12, lines 4-5 the terminology "void-type" is being considered vague and indefinite.

In claim 24, line 7 the terminology "void-type" is being considered vague and indefinite.

In claim 40, lines 5-6 the terminology "void-type" is being considered vague and indefinite.

The addition of the word "type' to an otherwise definite expression extends the scope of the expression to render it indefinite. *Ex Parte Copenhaver*, 109 USPQ 118 (Bd. App. 1955).

Claim Rejections - 35 USC § 103

- 3. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and

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the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

- 4. This application currently names joint inventors. In considering patentability of the claims under 35 U.S.C. 103(a), the examiner presumes that the subject matter of the various claims was commonly owned at the time any inventions covered therein were made absent any evidence to the contrary. Applicant is advised of the obligation under 37 CFR 1.56 to point out the inventor and invention dates of each claim that was not commonly owned at the time a later invention was made in order for the examiner to consider the applicability of 35 U.S.C. 103(c) and potential 35 U.S.C. 102(e), (f) or (g) prior art under 35 U.S.C. 103(a).
- 5. Claims 12-23 and 40 are rejected under 35 U.S.C. 103(a) as being unpatentable over Kimura, et al '362 (WO 01/27362 A1) in view of Japanese Abstract 2001-274167.

Kimura, et al '362 A1 teaches a silicon single-crystal wafer and a CZ method of making the same, wherein the wafer is doped with nitrogen and the whole surface is a V-rich region or in which the wafer is doped with nitrogen, an OSF region is provided in the surface, the LEP density in the OSF region is 20 pieces/cm² or less the OSF density in 1 x 10⁴ pieces/cm² or less. A substrate for an epitaxial wafer having few crystal defects is produced in the epitaxial layer when epitaxial growth on a CZ silicon single-crystal is doped with nitrogen.

The difference being that a slicing or "cutting" step is not taught by Kimura, et al. '362 A1.

Japanese Abstract '2001-274167 teaches a silicon single-crystal wafer being obtained by cutting a silicon single crystal which contains nitrogen at a concentration of

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> 1 x 10¹³/ cm³. When an epitaxial layer is caused to deposit on the wafer, an occurrence of stacking faults is reduced to < 0.5 defect/ cm² or dislocations over the whole surface of the wafer is reduced to < 0.5 dislocations/ cm². It would have been obvious to one of ordinary skill in the art to modify and optimize the product and method teachings, as taught by the Kimura, et al '362 A1 reference, to be enhanced by the teachings of the Japanese Abstract '167. The motivation being the production of high quality silicon single-crystals that have superior device characteristics and excellent IG ability for producing them.

A reference is good not only for what it teaches by direct anticipation but also for what one of ordinary skill might reasonably infer from the teachings. In re Opprect 12 USPQ 2d 1235, 1236 (CAFC 1989); In re Bode 193 USPQ 12; In re Lamberti 192 USPQ 278; In re Bozek 163 USPQ 545, 549 (CCPA 1969); In re Van Mater 144 USPQ 421; In re Jacoby 135 USPQ 317; In re LeGrice 133 USPQ 365; In re Preda 159 USPQ 342 (CCPA 1968).

Allowable Subject Matter

- 6. Claims 24-39 are allowed.
- 7. The following is an examiner's statement of reasons for allowance: The most relevant prior art of reference was the art submitted by the applicants. However, they do not teach nor fairly suggest singularly or in any combination thereof a method for producing a silicon wafer for epitaxial growth wherein a silicon wafer for epitaxial growth is produced by growing a silicon single crystal with doping nitrogen according to the CZ method, with controlling F/G (mm2/min x K) in the range of 0.30 or more where F

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(mm/min) is a rage of crystal growth and G (K/mm) is a temperature gradient near growth interface when the silicon single crystal is grown, and with controlling a passage time (min) at 1150 to 1050*C in the range of 40 minutes or more, in the region wherein at least the center of the wafer becomes V region in which the void defects are generated, and then slicing the grown silicon single crystal.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Any inquiry concerning this communication or earlier communications from the Examiner should be directed to Felisa Hiteshew whose telephone number is (571) 272-1463. The examiner can normally be reached on Mondays through Thursday from 5:30 AM to 4:00 PM with Fridays off.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Yogendra Gupta, can be reached on (571) 272-1316. The fax phone number for the organization where this application or proceeding is assigned is (571) 273-1463.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system. see

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http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866- 217-9197 (toll-free).

FELISA HITESHEW
PRIMARY EXAMINER

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